



Sheet 1 of 1

FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))

Attorney Docket No.: M&N-IT-465
Applic. No. 10/622,933

Applicant

Chee Hong Liau

Filing Date July 18, 2003
Group Art Unit 2858

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	A	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
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	I						

FOREIGN PATENT DOCUMENT

	J	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J						
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	Leslie Smith: "An Introduction to Neural Networks", XP - 001152218, Centre for Cognitive and Computational Neuroscience, University of Stirling, www.cs.stir.ac.uk , 2001
	P	The Math Works, Inc.: "Neural Network Toolbox 4", for designing and simulating neural networks, XP-001152219, www.mathworks.com , 2000

EXAMINER

DATE CONSIDERED

9/26/06

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609;
Draw line through citation if not in conformance and not considered. Include copy of this form with
next communication to applicant.

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: M&N-IT-465		Applic. No. Concurrently herewith	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Applicant Chee Hong Liau			
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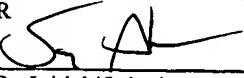
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
SP	A	5,684,946	11/97	Ellis et al.	—	—	
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FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL.
							YES
							NO
	J						
	K						
	L						
	M						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

SP	Zhao et al.: "Estimation of Switching Noise on Power Supply Lines in Deep Sub-Micron CMOS Circuits", IEEE, 13 th International Conference on VLSI Design, January 2000, pp. 168-73.
SP	Chakradhar: "Automatic Test Generation using Neural Networks", IEEE International Conference on Computer-Aided Design, November 7-10, 1988, pp. 416-19.

EXAMINER 	DATE CONSIDERED 9/22/06
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	